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\* The following papers have been selected to be published through IEEExplore

Design of an OTA circuit for low voltage applications.....1

Harmonic Tag with Probe-Fed Patch Antennas.....7

Within-Chip Bridged-Pattern Short Detection Using Spatially Distributed Kerf Test Structures in 7nm FinFET Technology.....11

On the Design of a 20 Channel Pin Parametric Measurement System for Post-Fabrication Testing.....14

Machine Learning Infused Software Testing for Mobile Device Development.....18

Co-design of a novel CMOS highly parallel, low-power, multi-chip Neural Network Accelerator in 28nm CMOS.....23

Gate Resistance Test Structures Bounded by Local Layout Density to Characterize Metal Gate Height Variation in 7nm FinFET Technology.....29

High-Speed Receiver Transient Modeling with Generative Adversarial Networks.....33